

# APPARATUS AND METHOD FOR DRIVING CIRCUIT PINS IN A CIRCUIT TESTING SYSTEM

## Abstract of the Disclosure

A circuit testing apparatus for testing a circuit under test. The circuit testing apparatus includes a controller for controlling signals being transferred between a circuit under test and the circuit testing apparatus. The circuit testing apparatus further includes a driver circuit for generating signals to be applied to the circuit under test. The driver includes a high speed slave chain and DC control loop chain coupled to the circuit under test. The high speed slave chain receives a differential voltage logic pulse train and converts the logic pulse train into a high speed current steering for producing the drive signal to be applied to the circuit under test. The DC control loop chain provides feedback paths for DC regulation of inputs of the high speed slave chain.

20070105010001